

- 2:00 D-89 INVITED—NEXT GENERATION X-RAY DETECTOR FOR IN-HOUSE XRD**
T. Taguchi, Rigaku Corporation, Tokyo, Japan
C. Broennimann, E.F. Eikenberry, DECTRIS Ltd, Villigen PSI, Switzerland
- 2:30 F-18 HIGH PERFORMANCE SILICON DRIFT DETECTORS WITH INTEGRATED FET FOR XRF ANALYSIS**
A. Niculae, H. Soltau, P. Lechner, A. Liebl, G. Lutz, R. Eckhard, PNSensor GmbH, Munich, Germany
L. Strüder, G. Schaller, F. Schopper, Semiconductor Laboratory of MPI, Munich, Germany
- 2:50 F-15 NOVEL SILICON DRIFT DETECTORS WITH ENHANCED RELIABILITY FOR INCREASING REQUIREMENTS OF ANALYTICAL APPLICATIONS**
O. Boslau, T. Eggert, J. Kemmer, A. Pahlke, S. Pahlke, R. Stoetter, F. Wiest, Ketek GmbH, Munich, Germany
- 3:10 BREAK**
- 3:40 F-16 PERFORMANCE OF A ROOM TEMPERATURE GAS PROPORTIONAL SCINTILLATION COUNTER IN X-RAY ANALYSIS OF METALLIC ALLOYS EXCITED WITH ALPHA PARTICLES**
F.I.G.M. Borges, S.J.C. do Carmo, T.H.V.T. Dias, F.P. Santos, F.P.S.C. Gil, A.M.F. Trindade, R.M. Curado da Silva, C.A.N. Conde, Universidade de Coimbra, Coimbra, Portugal
- 4:00 D-60 DETECTORS FOR DEMANDING X-RAY DIFFRACTION EXPERIMENTS**
L. Brügemann, H.-G. Krane, Bruker AXS, Karlsruhe, Germany
Y. Diawara, B. He, Bruker AXS Inc., Madison, WI
- 4:20 D-101 FAST XRPD MEASUREMENT OF POWDERS BY USING IMAGE-PLATE AND ROTATING ANODE SOURCE—COMPARISON WITH CONVENTIONAL BRAGG-BRENTANO DIFFRACTOMETER**
G. Kimmel, D. Moqilyanski, Ben-Gurion University of the Negev, Beer-Sheva, Israel